

# MgB<sub>2</sub> Thin Films on SiC Buffer Layers with Enhanced Critical Current Density at High Magnetic Fields

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(Received 2 July 2012; revised 2 August 2012; accepted 8 August 2012)

## Abstract

We have grown MgB<sub>2</sub> superconducting thin films on the SiC buffer layers by means of hybrid physical-chemical vapor deposition (HPCVD) technique. Prior to that, SiC was first deposited on Al<sub>2</sub>O<sub>3</sub> substrates at various temperatures from room temperature to 600°C by using the pulsed laser deposition (PLD) method in a vacuum atmosphere of ~10<sup>-6</sup> Torr pressure. All samples showed a high transition temperature of ~40 K. The grain boundaries of MgB<sub>2</sub> samples with SiC layer are greater in amount, compare to that of the pure MgB<sub>2</sub> samples. MgB<sub>2</sub> with SiC buffer layer samples show interesting change in the critical current density ( $J_c$ ) values. Generally, at both 5 K and 20 K measurements, at lower magnetic field, all MgB<sub>2</sub> films deposited on SiC buffer layers have low  $J_c$  values, but when they reach higher magnetic fields of nearly 3.5 Tesla,  $J_c$  values are enhanced. MgB<sub>2</sub> film with SiC grown at 600°C has the highest  $J_c$  enhancement at higher magnetic fields, while all SiC buffer layer samples exhibit higher  $J_c$  values than that of the pure MgB<sub>2</sub> films. A change in the grain boundary morphologies of MgB<sub>2</sub> films due to SiC buffer layer seems to be responsible for  $J_c$  enhancements at high magnetic fields.

*Keywords* : MgB<sub>2</sub> thin film, SiC buffer layer, critical current density.

## I. Introduction

The 39 K superconductor MgB<sub>2</sub> has attracted tremendous interest for its potential in high magnetic-field applications [1- 3]. MgB<sub>2</sub> possesses a number of attractive properties, including strongly coupled grain boundaries [4]. Within the past decade, there have been many attempts to enhance the high-field performance of MgB<sub>2</sub>, including using irradiation [5] and adding dopants such as carbon [6], SiC [7] and ZrB<sub>2</sub> [8]. Among these methods, carbon doping has proven to be an effective way to enhance

$H_{c2}$  and high-field  $J_c$  [9, 10]. An even more dramatic enhancement of  $H_{c2}$  has been seen in the case of carbon-doped MgB<sub>2</sub> films produced by hybrid physical-chemical vapor deposition (HPCVD) [11, 12]

Improving the  $J_c$  in MgB<sub>2</sub> films is important because attaining a high critical current is one of the prime requirements for practical applications of superconducting films [13]. Chromic *et al.* [14] fabricated MgB<sub>2</sub> thin films on SiC buffered Si substrates and Yao *et al.* [15] produced very thick MgB<sub>2</sub> films (60–140  $\mu\text{m}$ ) doped with SiC nanoparticles. These methods have successfully enhanced the  $J_c$  except for the MgB<sub>2</sub> thin films on SiC buffered Si substrates, although the samples showed lower superconducting transition

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temperatures comparing with the pure MgB<sub>2</sub>.

In this paper, we studied the effect of SiC buffered Al<sub>2</sub>O<sub>3</sub> substrate on MgB<sub>2</sub> thin films. This preliminary work was done for future project of growing SiC buffered MgB<sub>2</sub> thin films on metal hastelloy substrate. In this case, SiC buffer layers are needed for few reasons, one is to hinder the diffusion of the metal elements into the MgB<sub>2</sub> films, and also to provide the carbon doping needed to enhance  $J_c$  values, and another one is to minimize the lattice mismatch between the metal hastelloy and the MgB<sub>2</sub> films. By studying the conditions and effects of the SiC buffer layers toward MgB<sub>2</sub> films, we can draw a clear line of what to expect in the next study of SiC buffered hastelloy substrate.

## II. Experimental details

SiC buffer layers were first deposited on  $5 \times 10$  mm size Al<sub>2</sub>O<sub>3</sub> substrates by pulsed laser deposition (PLD) technique with various temperature of room temperature, 500° and 600°C. The deposition was conducted inside the vacuum chamber of  $\sim 10^{-6}$  Torr for 20 minutes with a SiC target (99.95 % purity). Laser beams were generated from a KrF excimer laser ( $\lambda=248$  nm). The pulse energy was set at 250 mJ with a repetition rate of 8 Hz.

MgB<sub>2</sub> thin films of  $\sim 180$  nm thickness were grown on SiC buffer-layer-deposited-sapphire substrates by using HPCVD technique. The films were heated up to 550°C in 200 Torr of ambient H<sub>2</sub> gas. Next, B<sub>2</sub>H<sub>6</sub> (5% B<sub>2</sub>H<sub>6</sub> + 95% H<sub>2</sub>) at 20 sccm was introduced into the quartz reactor to start the growth of MgB<sub>2</sub> films.

The growth time for all samples was around 15 minutes. Finally, the fabricated films were cooled down to room temperature in a flowing H<sub>2</sub> carrier gas.

The MgB<sub>2</sub> thin films were investigated by using X-ray diffraction (XRD), scanning electron microscopy (SEM), and a magnetic property measurement system (MPMS). Resistance measurements were carried out by using the standard four-probe method.

## III. Results and discussions

Fig. 1 shows XRD patterns of  $\theta$ - $2\theta$  scans of the SiC buffer layers deposited on the top of the Al<sub>2</sub>O<sub>3</sub> substrates. The SiC buffer layers fabricated on sapphire substrates with deposition temperatures of room temperature, 500°C and 600°C are labeled SiC RoomT, SiC 500, and SiC 600, respectively. The only substantial SiC peak is the (103) reflection, which shows that SiC is oriented with its  $c$ -axis normal to the substrate. Significant SiC intensities which began to develop with the increase of the deposition temperatures confirm that the films contain hexagonal textures in the film plane.

The temperature dependences of the resistance for MgB<sub>2</sub> thin films grown on SiC buffer layers at temperatures of room temperature, 500 °C, and 600 °C are shown in Fig. 2, respectively. The inset of Fig. 2 shows a magnified view near the superconducting transition temperature and the resistance values are normalized at 50 K. All samples showed a high transition temperature of  $\sim 40$  K and narrow superconducting transition width ( $\Delta T = T_{c,on} - T_{c0}$ ) of about 0.4 K, indicating good homogeneity of the samples. Little changes in  $T_c$  and  $\Delta T_c$  also suggest that SiC buffer layers have minimal effects on the superconducting properties of MgB<sub>2</sub>.

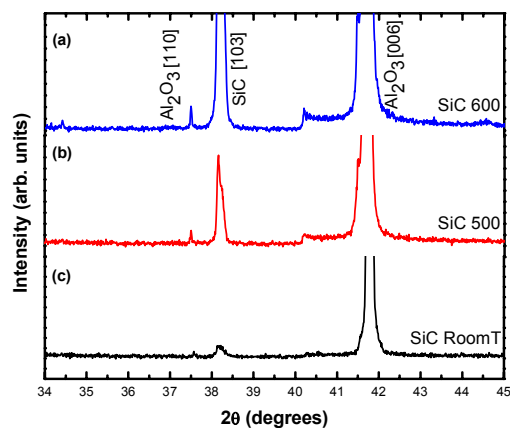


Fig. 1. X-ray diffraction patterns of SiC buffer layers grown inside PLD at temperatures: (a) 600 °C, (b) 500 °C, and (c) Room temperature

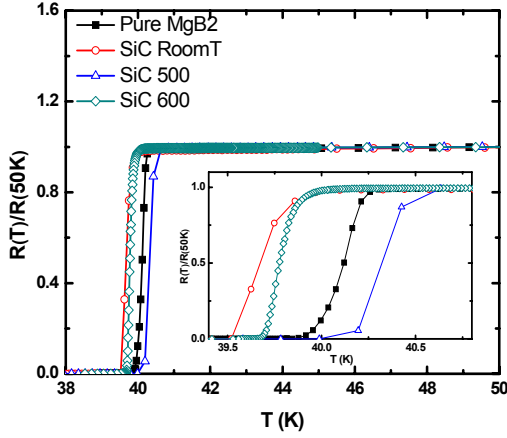


Fig. 2. Resistance as a function of temperature for  $\text{MgB}_2$  thin films grown on SiC buffer layers deposited on  $\text{Al}_2\text{O}_3$  substrates. The inset shows an enlarged view near the  $T_c$  and the resistance values are normalized by the resistance at 50 K.  $T_c$  is determined when the transition from normal-superconducting state starts indicated by  $T_{\text{conset}}$ .

The critical current densities ( $J_c$ ) of each film at 5 and 20 K were calculated from the M–H hysteresis loops by using Bean’s critical state model and plotted in the  $J_c - H$  relations, as shown in Fig. 3. The magnetization hysteresis measurements were performed by using an MPMS with applied fields varying from -5 T to 5 T, which are not shown here. Magnetic fields were applied perpendicular ( $H \perp ab$ ) to the film plane. At both 5 K and 20 K measurements, at lower magnetic field, all  $\text{MgB}_2$  films with SiC buffer layers had low  $J_c$  values, but when they reached high magnetic field of nearly 3.5 Tesla,  $J_c$  values were enhanced.  $\text{MgB}_2$  film with SiC grown at 600°C had the highest  $J_c$  enhancements at high magnetic fields, while all SiC-buffered samples exhibit higher  $J_c$ s than those of the pure  $\text{MgB}_2$  film. These results indicate that the SiC buffer layer deposited at 600°C provide the optimum condition for the  $J_c$  enhancement of  $\text{MgB}_2$  at high fields.

The surface morphologies of the SiC-buffered  $\text{MgB}_2$  thin films on  $\text{Al}_2\text{O}_3$  substrates were obtained using scanning electron microscopy (SEM). Fig. 4 shows that all SiC-buffered  $\text{MgB}_2$  thin films have hexagonal-like grain shapes. Compared to the pure  $\text{MgB}_2$  film, grains were large and bulky, which lead

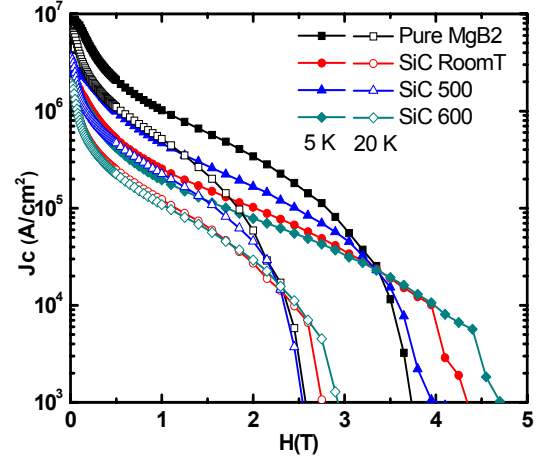


Fig. 3. The critical current density ( $J_c$ ) versus applied magnetic field at 5 and 20 K for pure and SiC buffer layered  $\text{MgB}_2$  thin films. The SiC 600 °C has the highest  $J_c$  enhancement and all SiC buffered samples show higher  $J_c$  values than the pure  $\text{MgB}_2$  thin film at high field region.

to less flat surface and poor connectivity between grains.

Jung *et al.* [16] has reported a simple method for the enhancement of  $J_c$  in  $\text{MgB}_2$  thick films on top of amorphous SiC impurity layers.  $J_c$  enhancements were observed through the whole magnetic field region. Their results suggest that the SiC particles along with the columnar grain boundaries in the  $\text{MgB}_2$  thick films serve as strong pinning centers.

On the other hand, we used crystalline SiC in our work, thus produced rougher  $\text{MgB}_2$  surface which result in huge  $J_c$  enhancements specifically at high fields. As it can be seen in the SEM images, the  $\text{MgB}_2$  on SiC buffer layers are showing smaller density of grain boundaries and larger pores on the  $\text{MgB}_2$  surface which are contrary to the pure  $\text{MgB}_2$  surface. These surface defects may also contribute to the existence of the pinning centers in  $\text{MgB}_2$ .

However, the effect of carbon doping in the form of SiC buffer layer has not thoroughly investigated yet in our current work. A further research on how carbon doping in the form of SiC buffer layer affecting the  $J_c$  values of the  $\text{MgB}_2$  films is needed in order to have more comprehensive understanding.

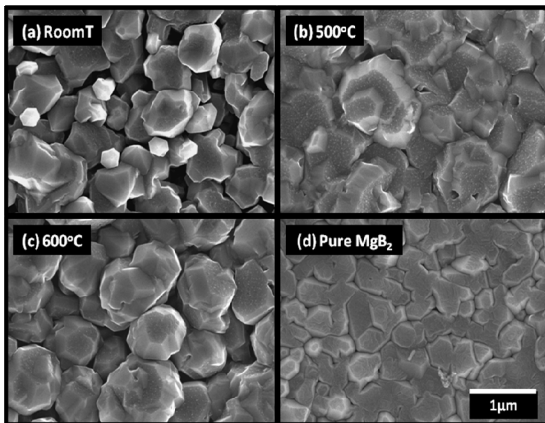


Fig. 4. SEM images of the MgB<sub>2</sub> thin films grown on SiC buffer layers: (a) SiC Room temperature, (b) SiC 500 °C, (c) SiC 600 °C, (d) Pure MgB<sub>2</sub> on Al<sub>2</sub>O<sub>3</sub>.

#### IV. Conclusions

In conclusion, the  $J_c$  enhancement of the MgB<sub>2</sub> thin films with SiC buffer layers was shown to have an interesting behavior. At high field region, the  $J_c$  values of MgB<sub>2</sub> films with SiC buffer layer were uniquely enhanced, while an opposite behavior was observed at low field region. The SiC buffer layer which was deposited inside the PLD chamber at 600 °C turned out to have the highest  $J_c$  enhancement at high fields. From the surface morphology analysis, changes in the shape and density of grain boundaries of MgB<sub>2</sub> due to crystalline SiC buffer layer may be considered as a dominant pinning mechanism in MgB<sub>2</sub> thin films and could play an important role in enhancing  $J_c$  at high magnetic fields. A future study on how carbon doping in the form of SiC buffer layer affecting the  $J_c$  values of the MgB<sub>2</sub> films will be needed to obtain more sufficient understanding on the pinning mechanism of MgB<sub>2</sub> films.

#### Acknowledgements

This work was supported by a grant of the Global Partnership Program through the NRF funded by the Ministry of Education, Science and Technology (M60602000012).

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